IDS #8 Sheet 1 of 7

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. MI22-1742

APPLICANT: Kristy A. Campbell et al.

SERIAL NO. 09/943,187

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BD.	AA	3,622,319	11/23/71	Sharp		96	27		
	АВ	3,743,847	07/03/73	Boland		250	510	-	,
	AC	4,269,935	05/26/81	Masters et al.		430	323		
	AD	4,312,938	01/26/82	Drexler et al.		430	496		
	AE	4,320,191	03/16/82	Yoshikawa et al.		430	296		
	AF	4,795,657	01/03/89	Formigoni et al.		427	96		
	AG	4,847,674	07/11/89	Silwa et al.	, ,,,,,,	357	67	1	-
	АН	5,177,567	01/05/93	Klersy et al.		257	4		
	Al	5,219,788	06/15/93	Abernathey et al.		437	187		
	AJ	5,726,083	03/10/98	Takaishi		438	210		
V	AK	5,751,012	05/12/98	Wolstenholme et al.		257	5		
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	AM	OTHER RE	FERENCES (i	including Author, Title, D	ate, Pertinent Pa	ges, Etc	.)		
NT)	AN	Das et al.,	Theory of the	characteristic curves	of the silver cha	alcogenic	de glass i	norganic	
	-			PL. PHYS. LETT., No. 18					
+	AO		*	hybrid resist process w				ol. 333	
				APHY pp. 24-29 (1982)					
	AP			rials Characterization of	Silver Chalcogo	enide Pr	ogrammat	ole Metalli	izatio
<b>√</b>				e University, pp. title pa					
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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PRADE	<b>&gt;</b>		U	S. PATENT DOCUMEN	TS				
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KBP	AA	5,789,277	08/04/98	Zahorik et al.		438	95		
	АВ	5,841,150	11/24/98	Gonzalez et al.		257	3		
	AC	5,920,788	07/06/99	Reinberg		438	466		
	AD	5,998,066	12/07/99	Block et al.		430	5		•
	AE	6,077,729	06/20/00	Harshfield		438	128		. •
	AF	6,236,059 B1	05/22/01	Wolstenholme et al.		257	3		<sup>4</sup> E
	AG	6,297,170 B1	10/02/01	Gabriel et al.		438	738 774 3		
	АН	6,300,684 B1	10/09/01	Gonzalez et al.		257			
	Al	6,316,784 B1	11/13/01	Zahorik et al.		257			•
	AJ	6,329,606 B1	12/11/01	Freyman et al.		174	74 260		,
V	AK	6,348,365	02/19/02	Moore et al.		438	130	:	
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	AL		<del>                                     </del>					163	140
	АМ								
	· · · · · ·	OTHER REF	ERENCES (i	ncluding Author, Title, D	ate, Pertinent Pa	ges, Etc	.)		
KBD	AN	Holmquist et	Holmquist et al., Reaction and Diffusion in Silver-Arsenic Chalcogenide Glass Systems,						
		62 J. A	MER. CERAM	c Soc., Nos. 3-4, pp.	183-188 (MarA	pr. 1979	9).		
	AO	Huggett et a	I., Developm	ent of silver sensitized	germanium sele	enide ph	otoresist	by reacti	ve
		sputter	etching in S	F <sub>6</sub> , 42 APPL. PHYS. LE	TT., No. 7, pp. 5	592-594	(April 19	83).	
√ 、	AP	Kawaguchi e	t al., Mecha	nism of photosurface o	leposition, 164-1	66 J. No	ON-CRYST.	SOLIDS,	
		. pp. 123	11-1234 (199	3).		<del></del>			
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KBP	AA	6,376,284 B1	04/23/02	Gonzalez et al.	438	129						
	AB	6,391,688 B1	05/21/02	Gonzalez et al.	438	128		٠				
	AC	6,414,376 B1	07/02/02	Thakur et al.	257	640						
	AD	6,418,049 B1	07/09/02	Kozicki et al.	365	174		·				
<b>V</b>	AE	6,423,628 B1	07/23/02	Li et al.	438	622		. 2				
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BD	AN	McHardy et	McHardy et al., The dissolution of metals in amorphous chalcogenides and the effects of									
		electro	on and ultravi	olet radiation, 20 J. PHYS. C: SOLI	D STATE PHY	s., pp. 40	55-4075	(1987				
	АО	Miyatani, <i>El</i>	ectrical Porpe	erties of Ag₂Se, 13 J. Phys. Soc.	Japan, p. 31	7 (1958).						
			· · · · · · ·									
V	АР	Mizusaki et	al. Kinetic S	tudies on the Selenization of Silve	er, 47 Bul. C	CHEM. SOC	JAPAN,,	No. 1				
•		pp. 28	51-2855 (Nov	vember 1974).								
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KBP	AN	Owen et al.,	Metal-Chalco	ogenide Photoresists for High Resolu	ution Litho	graphy and	d Sub-Mic	ron
/ /"		Structu	res, Nanostr	UCTURE PHYSICS AND FABRICATION, p	p. 447-45	1 (Academ	ic Press,	1989
	AO	Safran et al.	, TEM study	of Ag₂Se developed by the reaction	of polyci	ystalline s	ilver films	and
		seleniu	<i>n</i> , 317 Thin	SOLID FILMS, pp. 72-76 (1998).				
∤	АР	Shimizu et a	I., The Photo	-Erasable Memory Switching Effect	of Ag Pho	oto-Doped	Chalcogei	nide
		Glasses	s, 46 Bul. Ch	HEM. SOC. JAPAN, No. 12, pp. 3662-	3665 (Dec	ember 197	'3). ·	
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1BD	AN	Somogyi et	al., Tempera	ture Dependence of the Carrier I	Mobility in Ag	Se Layers	Grown o	on
		NaCl	and SiO <sub>x</sub> Sub	ostrates, 74 ACTA PHYSICA HUNGAR	RICA, No. 3, p	p. 243-25	5 (1994).	
	AO	Tai et al.,	Multilevel Ge-	Se film based resist systems, SF	PIE Vol. 333	SUBMICRON	LITHOGR	АРНҮ,
		pp. 32	2-39 (March 1	982).			~ <del>~~</del>	
	АР	Tai et al.,	Submicron op	tical lithography using an inorgan	ic resist/polyn	ner bilevel	scheme,	
,		17 J.	Vac. Sci. Te	chnol., No. 5, pp. 1169-1176 (Se	pt./Oct. 1980)			
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APPLICANT: Kristy A. Campbell et al.

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		Multifra	ctal Aggreg	ates, Arizona State Uni	versity, pp. tit	le page-16	88 (UMI C	o., May	1998).			
	AO	West et al.,	Equivalent	Circuit Modeling of the	rcuit Modeling of the Ag As <sub>0.24</sub> S <sub>0.36</sub> Ag <sub>0.40</sub>  Ag System Prepared by							
		Photodi	ssolution o	f Ag, 145 J. Electrocher	m. Soc., No.	9, pp. 297	'1-2974 (S	eptember	1998			
<i>\</i>	АР	Yoshikawa e	t al., A ne	v inorganic electron res	ist of high co	ntrast, 31	APPL. PHY	'S. LETT.,	No. 3			
		pp. 161	-163 (Augı	st 1977).	. <u>-</u>	<del>_,_</del> ·_,						
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